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S./	0	G. Bruno, et al., "Study of the NF <sub>3</sub> plasma cleaning of reactors for amorphous silicon deposition," May/June 199 © 1994 American Vacuum Society, J. Vac. Sci. Technol. A 12(3), pages 690-698.								
F.S./	P	Srihari Ponnekanti, et al., "Failure mechanisms of anodized aluminum parts used in chemical vapor deposition chambers," © 1996 American Vacuum Society, J. Vac. Sci. Technol. A 14(3), pages 1127-1131.								
F.S.	Q	Hsin-Pai Hsueh, et al., "Ion energy distributions and optical emission spectra in NF <sub>x</sub> -based process chamber cleaning plasmas," © 2001 American Vacuum Society, J. Vac. Sci. Technol. B 19(4), pages 1346-1357.								
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